10681116_CLS
Most Frequently Occurring Classifications of Patents Returned From A Search of 10681116 on March 17, 2004

Original Classifications

3	348/351
2	257/797
2	313/413
2	324/751
2	347/55

Cross-Reference Classifications

5	348/356
2	250/201.7
2	257/620
2	313/414
2	348/355
2	361/225
2	396/89

Combined Classifications

5	348/356
3	348/351
2	250/201.7
2	250/396R
2	250/492.2
2	257/620
2	257/797
2	313/413
2	313/414
2	324/751
2	347/55
2	348/354
2	348/355
2	361/225
2	396/89
2	716/4

10681116_CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 10681116 on March 17, 2004

5 348/356 (0 OR, 5 XR)
Class 348 : TELEVISION
348/207.99 CAMERA, SYSTEM AND DETAIL
348/335 .Optics
348/345 ..Focus control
348/349 ...Using image signal
348/354 ....By analyzing high frequency component
348/356 .....Detection of peak or slope of image signal

3 348/351 (3 OR, 0 XR)
Class 348 : TELEVISION
348/207.99 CAMERA, SYSTEM AND DETAIL
348/335 .Optics
348/345 ..Focus control
348/349 ...Using image signal
348/351 ....With oscillation of lens or sensor to optimize error signal

2 250/201.7 (0 OR, 2 XR)
Class 250 : RADIANT ENERGY
250/200 PHOTOCELLS; CIRCUITS AND APPARATUS
250/201.1 .Photocell controls its own optical systems
250/201.2 ..Automatic focus control
250/201.7 ...Based on contrast

2 250/396R (1 OR, 1 XR)
Class 250 : RADIANT ENERGY
250/396R WITH CHARGED PARTICLE BEAM DEFLECTION OR FOCUSSING

2 250/492.2 (1 OR, 1 XR)
Class 250 : RADIANT ENERGY
250/492.1 IRRADIATION OF OBJECTS OR MATERIAL
250/492.2 .Irradiation of semiconductor devices

2 257/620 (0 OR, 2 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/618 PHYSICAL CONFIGURATION OF SEMICONDUCTOR (E.G., MESA, BEVEL, GROOVE, ETC.)
257/620 .With peripheral feature due to separation of smaller semiconductor chip from larger wafe

r (e.g., scribe region, or means to prevent edge effects such as leakage current at peripheral chip separation area)

2 257/797 (2 OR, 0 XR)
Class 257 : ACTIVE SOLID-STATE DEVICES
257/797 ALIGNMENT MARKS

2 313/413 (2 OR, 0 XR)
Class 313 : ELECTRIC LAMP AND DISCHARGE DEVICES
313/364 CATHODE RAY TUBE
313/409 .Plural beam generating or control
313/413 ..With deflection

2 313/414 (0 OR, 2 XR)
Class 313 : ELECTRIC LAMP AND DISCHARGE DEVICES
313/364 CATHODE RAY TUBE
313/409 .Plural beam generating or control
313/414 ..With focusing and accelerating electrodes

2 324/751 (2 OR, 0 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/500 FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS
324/537 .Of individual circuit component or element
324/750 ..System sensing fields adjacent device under test (DUT)
324/751 ...Using electron beam probe

2 347/55 (2 OR, 0 XR)
Class 347 : INCREMENTAL PRINTING OF SYMBOLIC INFORMATION
347/1 INK JET
347/20 .Ejector mechanism (i.e., print head)
347/54 ..Drop-on-demand
347/55 ...With electric field ejection (applied to fluid)

2 348/354 (1 OR, 1 XR)
Class 348 : TELEVISION
348/207.99 CAMERA, SYSTEM AND DETAIL
348/335 .Optics
348/345 ..Focus control
348/349 ...Using image signal
348/354 ....By analyzing high frequency component

2 348/355 (0 OR, 2 XR)
Class 348 : TELEVISION
348/207.99 CAMERA, SYSTEM AND DETAIL
348/335 .Optics
348/345 ..Focus control
348/349 ...Using image signal
348/354 ....By analyzing high frequency component
348/355 .....Plural high frequencies

2 361/225 (0 OR, 2 XR)
Class 361 : ELECTRICITY: ELECTRICAL SYSTEMS AND DEVICES

361/225 ELECTRIC CHARGING OF OBJECTS OR MATERIALS

2 396/89 (0 OR, 2 XR)
Class 396 : PHOTOGRAPHY
396/89 WITH EXPOSURE OBJECTIVE FOCUSING MEANS, FOCUSING AID, OR RANGEFINDING MEANS

2 716/4 (1 OR, 1 XR)
Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF CIRCUIT OR SEMICONDUCTOR MASK
716/1 CIRCUIT DESIGN
716/4 .Testing or evaluating